

Search Notes

Application No.

10/092,887

Examiner

Scott R. Wilson

Applicant(s)

BRANDES ET AL.

Art Unit

2826

SEARCHED

Class	Subclass	Date	Examiner
257	76,77	8/11/04	smw
438	105,931	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated EAST search	8/11/04	smw

EAST 110-092037 - Amorphous SiC window coating.wsp-1				SEARCH		RESULTS		DETAILS		EDIT	
File View Edit Tools Window Help				11		4888 hits 49 04:59 12/10/02 2:14 PM 12/10/02					
Hit#	Search Text					Hit#	Time Stamp				
1	1168	(amorphous adj silicon ADJ carbide) WITH (coating or layer)						USPAT; US-PGPUB; EPO; 2004/08/11 15:32			
								JPO; DERWENT; IBM_TDB			
2	1256	257/76,77.ccls. 438/105,931.ccls.						USPAT; US-PGPUB; EPO; 2002/10/10 14:56			
								JPO; DERWENT; IBM_TDB			
3	2	(amorphous adj silicon ADJ carbide) and (electromagnetic adj interference)						USPAT; US-PGPUB; EPO; 2002/10/10 14:57			
								JPO; DERWENT; IBM_TDB			
4	72	(257/76,77.ccls. 438/105,931.ccls.) and (amorphous adj silicon ADJ carbide)						USPAT; US-PGPUB; EPO; 2004/08/12 11:55			
								JPO; DERWENT; IBM_TDB			
5	13	((257/76,77.ccls. 438/105,931.ccls.) and (amorphous adj silicon ADJ carbide)) and (transparent with light)						USPAT; US-PGPUB; EPO; 2002/12/12 13:16			
								JPO; DERWENT; IBM_TDB			
6	1	((257/76,77.ccls. 438/105,931.ccls.) and (amorphous adj silicon ADJ carbide)) and (electromagnetic with interference)						USPAT; US-PGPUB; EPO; 2002/10/10 16:57			
								JPO; DERWENT; IBM_TDB			
7	1	((257/76,77.ccls. 438/105,931.ccls.) and (amorphous adj silicon ADJ carbide)) and (emi)						USPAT; US-PGPUB; EPO; 2002/10/10 16:56			
								JPO; DERWENT; IBM_TDB			
8	2	(amorphous adj silicon ADJ carbide) and (emi)						USPAT; US-PGPUB; EPO; 2002/10/21 13:16			
								JPO; DERWENT; IBM_TDB			
9	3	(amorphous adj silicon ADJ carbide) and (electromagnetic with interference)						USPAT; US-PGPUB; EPO; 2002/10/11 14:38			
								JPO; DERWENT; IBM_TDB			
10	2	6031250.pn.						USPAT; US-PGPUB; EPO; 2002/10/10 17:08			
								JPO; DERWENT; IBM_TDB			
11	2	6268229.pn.						USPAT; US-PGPUB; EPO; 2002/10/10 17:09			
								JPO; DERWENT; IBM_TDB			
12	77	((electromagnetic adj interference) with shield) same film						USPAT; US-PGPUB; EPO; 2002/12/12 13:16			
								JPO; DERWENT; IBM_TDB			
13	13	((electromagnetic adj interference) with shield) same (thin adj film)						USPAT; US-PGPUB; EPO; 2002/12/12 13:16			
								JPO; DERWENT; IBM_TDB			
14	6	("5270488" "5153379" "5166772").pn.						USPAT; US-PGPUB; EPO; 2002/10/11 14:07			
								JPO; DERWENT; IBM_TDB			
15	106	(amorphous adj silicon ADJ carbide) same (conductivity or resistivity)						USPAT; US-PGPUB; EPO; 2002/10/11 14:50			
								JPO; DERWENT; IBM_TDB			
16	104	(amorphous adj silicon ADJ carbide) with (conductivity or resistivity)						USPAT; US-PGPUB; EPO; 2002/12/12 13:16			
								JPO; DERWENT; IBM_TDB			
17	9	(amorphous adj silicon ADJ carbide) with (conductivity or resistivity) and omega						USPAT; US-PGPUB; EPO; 2002/10/11 15:08			
								JPO; DERWENT; IBM_TDB			
18	9	(amorphous adj silicon ADJ carbide) with (conductivity or resistivity) and "omega"						USPAT; US-PGPUB; EPO; 2002/10/11 15:09			
								JPO; DERWENT; IBM_TDB			
110-092037				12/10/02							
110-092037				12/10/02							

updated EAST 8/11/04

EAST-10-092887: Amorphous SiC window config.wsp:1				10/11	
File View Edit Tools Window Help				10/11	
[Icons]				[Icons]	
Line	Area	Search Text	DBs	Time Stamp	
18	9	(amorphous adj silicon ADJ carbide) with (conductivity or resistivity) and "omega"	USPAT; US-PGPUB; EPO; 2002/10/11 15:09 JPO; DERWENT; IEM_TDB		
19	0	(amorphous adj silicon ADJ carbide) with (conductivity or resistivity) and thickness and ".mu."	USPAT; US-PGPUB; EPO; 2002/10/16 12:36 JPO; DERWENT; IEM_TDB		
20	63	(amorphous adj silicon ADJ carbide) with (conductivity or resistivity) and thickness	USPAT; US-PGPUB; EPO; 2002/10/16 14:45 JPO; DERWENT; IEM_TDB		
21	1	(amorphous adj silicon ADJ carbide) with (conductivity or resistivity) and thickness and glue	USPAT; US-PGPUB; EPO; 2002/10/16 13:27 JPO; DERWENT; IEM_TDB		
22	50	(amorphous adj silicon ADJ carbide) and ((glue or bonding or adhesive or bonded) adj layer)	USPAT; US-PGPUB; EPO; 2002/12/12 13:17 JPO; DERWENT; IEM_TDB		
23	13	(amorphous adj silicon ADJ carbide) with sensor	USPAT	2002/10/16 14:56	
24	6	(amorphous adj silicon ADJ carbide) with sensor and temperature	USPAT	2002/10/17 14:43	
25	0	(amorphous adj silicon ADJ carbide) with sensor same temperature	USPAT	2002/10/16 14:56	
26	2	(amorphous adj silicon ADJ carbide) with sensor and (high adj temperature)	USPAT; US-PGPUB; EPO; 2002/10/17 14:03 JPO; DERWENT; IEM_TDB		
27	1	(amorphous adj silicon ADJ carbide) with sensor and (high adj temperature) and doped	USPAT; US-PGPUB; EPO; 2002/10/17 14:04 JPO; DERWENT; IEM_TDB		
28	1	(amorphous adj silicon ADJ carbide) same sensor same (high adj temperature) same doped	USPAT; US-PGPUB; EPO; 2002/10/17 14:05 JPO; DERWENT; IEM_TDB		
29	3	(amorphous adj silicon ADJ carbide) and sensor same (high adj temperature) same doped	USPAT; US-PGPUB; EPO; 2002/10/17 14:06 JPO; DERWENT; IEM_TDB		
30	1	(amorphous adj silicon ADJ carbide) with diffusion adj barrier	USPAT	2004/08/11 14:17	
31	4	4109271.pn.	USPAT; US-PGPUB; EPO; 2002/10/17 15:20 JPO; DERWENT; IEM_TDB		
32	2	4451119.pn.	USPAT; US-PGPUB; EPO; 2002/10/17 15:20 JPO; DERWENT; IEM_TDB		
33	148	(amorphous adj silicon ADJ carbide) with (thin adj film)	USPAT; US-PGPUB; EPO; 2002/12/12 13:17 JPO; DERWENT; IEM_TDB		
34	0	(amorphous adj silicon ADJ carbide) WITH (coating or layer) and @pd>20021210	USPAT; US-PGPUB; EPO; 2002/12/12 13:17 JPO; DERWENT; IEM_TDB		
35	0	(257/76,77.ccls. 438/105,931.ccls.) and (amorphous adj silicon ADJ carbide) and @pd>20021210	USPAT; US-PGPUB; EPO; 2002/12/12 13:18		
[Icons]				36/36	

181 Details 10/5/19

☒ Silt
 ☒ Detritus
 ☒ Rock Silt